## USING OPTICAL EMISSION SPECTROSCOPY TO IMPROVE EQUIPMENT UPTIME FOR AN AL2O3 ALD PROCESS \*

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Installed OES unit with heater blankets



Typical emission spectra of an Al2O3 ALD process



Typical monitoring of chamber affluent wavelength

## SYSTEM INFORMATION



The Lightwind system monitors process chemistry via plasma-induced Optical Emission Spectroscopy (OES).



Wavelength time trend of a long chamber coat. There is a distinct shape of the trend which indicates that the chamber is ready for post chamber maintenance release.



Wavelength time trend of two successive short coats ( <sup>1</sup>/<sub>2</sub> the time of the long coat ). This shows a repeatable "seasoning" curve in the same process chamber. Keeping this signature in mind a higher gas flow coat was attempted.







These charts indicate that the same seasoning curve can be attained with a simple change to the coating recipe.







By understanding the response from the chamber affluent during chamber coating, qualification time (time required to prepare a processing chamber for production material processing) can be reduced from 6hours to 6min.



In this example, precursor chemical suppliers were compared by overlapping full spectra. Critical wavelengths were previously indentified as shown above. Using OES provided additional information regarding the precursor chemical composition from both suppliers.





Here OES monitoring was used to evaluate a new pump trap design. Shortly after installation, the intensity of the monitored wavelength decreased leading to an early detection of a trap failure.

The use of OES provides critical information regarding processing system integrity before and after a schedule maintenance. Here is an example whereby OES data was utilized after a precursor bottle fill. This coupled with an in-situ precursor fill system drastically reduced the total time required.



By switching to an AutoRefill System and then confirming chamber integrity post the maintenance with OES data, total time reduced by 6 hours.